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Complete if Known Substitute for form 1449A/B/PTO 09/816,004-Conf. #5183 Application Number INFORMATION DISCLOSURE Filing Date March 22, 2001 STATEMENT BY APPLICANT First Named Inventor Masakazu Suzuoki Art Unit 2144 (Use as many sheets as necessary) J. R. Maniwang Examiner Name of 1 Attorney Docket Number **SCEI 3.0-054** Sheet 1

U.S. PATENT DOCUMENTS						
Examiner Initials*	Cite No.1	Document Number	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Cotumns, Lines, Where Relevant Passages or Relevant Figures Appear	
		Number-Kind Code ² (if known)	MM-DD-YYYY			
J	AA*	US-2002/0052914-A1	05-02-2002	Zalewski et al.		
	AB*	US-5,037,173	08-06-1991	SAMPSELL et al.		
	AC*	US-5,056,000	10-08-1991	CHANG, ROBIN		
	AD*	US-5,093,879-A	03-03-1992	BREGMAN et al.		
	AE*	US-5,131,054	07-14-1992	SMITH, STEPHEN J.		
	AF*	US-5,487,146-A	01-23-1996	GUTTAG et al.		
	AG*	US-5,497,465-A	03-05-1996	CHIN et al.		
	AH*	US-5,581,777-A	12-03-1996	KIM et al.		
	Al*	US-5,652,853	07-29-1997	Duvalsaint et al.		
	AJ*	US-5,940,870-A	08-17-1999	CHI et al.		
	AK*	US-6,173,389-B1	01-09-2001	PECHANEK et al.		
	AL*	US-6,209,065-B1	03-27-2001	VAN DOREN et al.		
	AM*	US-6,334,139-B1	12-25-2001	Takashi Sakakura		
	AN*	US-6,341,338	01-22-2002	Dennie		
	AO*	US-6,360,303	03-19-2002	Wisler et al.		
	AP*	US-6,467,012-B1	10-15-2002	ALVAREZ et al.		
	AQ*	US-6,480,941	11-12-2002	Franke et al.		
	AR*	US-6,510,496	01-21-2003	Tarui et al.		
	AS*	US-6,510,498		Holzle et al.		
	AT⁴	US-6,647,208-B1	11-11-2003	KIRBY, ALAN J.		
1	AU*	US-6,965,974	11-15-2005	Bays et al.		

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
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